

March 1994 Revised November 1999

74ABT2240

Octal Buffer/Line Driver with 25 Ω Series Resistors in the Outputs

General Description

The ABT2240 is an inverting octal buffer and line driver designed to drive the capacitive inputs of MOS memory drivers, address drivers, clock drivers, and bus-oriented transmitters/receivers.

The 25Ω series resistors in the outputs reduce ringing and eliminate the need for external resistors.

Features

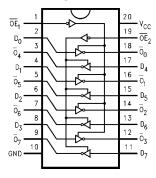
- Guaranteed latchup protection
- High impedance glitch-free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability

Ordering Code:

Order Number	Package Number	Package Description
74ABT2240CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ABT2240CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT2240CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74ABT2240CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Devices also available in Tape and Reel. Specify by appending letter suffix "X" to the ordering code.

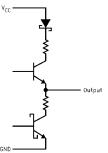
Connection Diagram



Pin Descriptions

Pin Names	Descriptions
$\overline{OE}_1, \overline{OE}_2$	Output Enable Input (Active LOW)
D ₀ –D ₇	Data Inputs
$\overline{O}_0 - \overline{O}_7$	Outputs

Schematic of Each Output



Truth Table

OE ₁	I ₀₋₃	<u></u>	OE ₂	I ₄₋₇	<u></u>
Н	Х	Z	Н	Х	Z
L	Н	L	L	Н	L
L	L	Н	L	L	Н

- H = HIGH Voltage Level
- L = LOW Voltage Level X = Immaterial
- Z = High Impedance

Absolute Maximum Ratings(Note 1)

Storage Temperature -65°C to +150°C

 $\begin{array}{lll} \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \mbox{Junction Temperature under Bias} & -55^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{V}_{\mbox{CC}} \mbox{ Pin Potential to Ground Pin} & -0.5V \mbox{ to } +7.0V \\ \end{array}$

Input Voltage (Note 2) -0.5V to +7.0V Input Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Any Output

in the Disabled or

Power-off State -0.5 V to 5.5 V in the HIGH State $-0.5 \text{V to } \text{V}_{\text{CC}}$

Current Applied to Output

in LOW State (Max) $\qquad \qquad \text{twice the rated I}_{\text{OL}} \ (\text{mA})$

DC Latchup Source Current

(Across Comm Operating Range) -300 mA
Over Voltage Latchup (I/O) 10V

Recommended Operating Conditions

Free Air Ambient Temperature -40°C to +85°C Supply Voltage +4.5V to +5.5V

Minimum Input Edge Rate ($\Delta V/\Delta t$)

Data Input 50 mV/ns
Enable Input 20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

V _{IH} Input HIGH Voltage 2.0 V Recognized HIGH Signal V _{IL} Input LOW Voltage 0.8 V Recognized LOW Signal V _{CD} Input Clamp Diode Voltage -1.2 V Min I _{IN} = -18 mA V _{OH} Output HIGH 2.5 V Min I _{OH} = -3 mA V _{OL} Output LOW Voltage 0.8 V Min I _{OH} = -32 mA V _{OL} Output LOW Voltage 0.8 V Min I _{OH} = -32 mA V _{OL} Output HIGH Current 1 μA Max V _{IN} = 2.7V (Note 3) V _{IN} = 0.00 1 μA Max V _{IN} = 2.7V (Note 3) V _{IN} = V _{CC} I _{BVI} Input LOW Current -1 μA Max V _{IN} = 0.5V (Note 3) V _{IN} = 0.5V (Note 3) V _{IN} = 0.0V V _{ID} Input Leakage Test V 0.0 I _{ID} = 1.9 μA All Other Pins Grounded I _{OZH} Output Leakage Current 10 μA 0 - 5.5V V _{OUT} = 2.7V; OEn = 2.0V I _{OZL} Output Leakag	LOW Signal A A A Note 3)
V _{CD} Input Clamp Diode Voltage -1.2 V Min I _{IN} = -18 mA	A Note 3)
VoH	Note 3)
Voltage V Min I _{OH} = -32 mA	Note 3)
Vol. Output LOW Voltage 0.8 V Min IoL = 15 mA	Note 3)
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Note 3)
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I_{OZH} Output Leakage Current 10 μA $0-5.5V$ $V_{OUT} = 2.7V$; $\overline{OE}n = 2.0V$ I_{OZL} Output Leakage Current -10 μA $0-5.5V$ $V_{OUT} = 0.5V$; $\overline{OE}n = 2.0V$ I_{OS} Output Short-Circuit Current -275 mA Max $V_{OUT} = 0.0V$ I_{CEX} Output HIGH Leakage Current 50 μA Max $V_{OUT} = V_{CC}$ I_{ZZ} Bus Drainage Test 100 μA 0.0 $V_{OUT} = 5.5V$; All Others GNI	
	ns Grounded
$\begin{tabular}{l l l l l l l l l l l l l l l l l l l $	/; OEn = 2.0V
I_{CEX} Output HIGH Leakage Current 50 μA Max $V_{OUT} = V_{CC}$ I_{ZZ} Bus Drainage Test 100 μA 0.0 $V_{OUT} = 5.5V$; All Others GNI	/; OEn = 2.0V
I_{ZZ} Bus Drainage Test 100 μ A 0.0 V_{OUT} = 5.5V; All Others GNI	/
	;
locu Power Supply Current 50 uA Max All Outputs HIGH	/; All Others GND
Towar Supply Surroll	HIGH
I _{CCL} Power Supply Current 30 mA Max All Outputs LOW	LOW
I_{CCZ} Power Supply Current 50 μA Max $\overline{OE}n = V_{CC}$	
All Others at V _{CC} or GND	t V _{CC} or GND
I_{CCT} Additional Outputs Enabled 1.5 mA $V_1 = V_{CC} - 2.1V$	2.1V
I_{CC} /Input Outputs 3-STATE 1.5 mA Max Enable Input $V_1 = V_{CC} - 2.1^{\circ}$	t $V_I = V_{CC} - 2.1V$
Outputs 3-STATE 50 μA Data Input $V_1 = V_{CC} - 2.1 V$	$V_1 = V_{CC} - 2.1V$
All Others at V _{CC} or GND	t V _{CC} or GND
I _{CCD} Dynamic I _{CC} No Load mA/ Outputs OPEN	EN
(Note 3) $0.1 MHz \overline{OEn} = GND \text{ (Note 4)}$	(Note 4)
One Bit Toggling, 50% Duty	gling, 50% Duty Cycle

Note 3: Guaranteed, but not tested.

Note 4: For 8 bits toggling, $I_{CCD} < 0.8 \text{ mA/MHz}.$

AC Electrical Characteristics

Symbol	Parameter		$T_A = +25$ °C $V_{CC} = +5V$ $C_L = 50 \text{ pF}$		V _{CC} = 4.	C to +85°C .5V–5.5V 50 pF	Units
		Min	Тур	Max	Min	Max	
t _{PLH}	Propagation	1.0		4.9	1.0	4.9	ns
t _{PHL}	Delay Data to Outputs	1.5		5.3	1.5	5.3	115
t _{PZH}	Output Enable	1.5		6.6	1.5	6.6	ns
t_{PZL}	Time	2.7		6.9	2.7	6.9	115
t _{PHZ}	Output Disable	1.9		6.4	1.9	6.4	20
t _{PLZ}	Time	1.9		6.4	1.9	6.4	ns

Capacitance

Symbol	Parameter	Тур	Units	Conditions T _A = 25°C
C _{IN}	Input Capacitance	5.0	pF	V _{CC} = 0V
C _{OUT} (Note 5)	Output Capacitance	9.0	pF	V _{CC} = 5.0V

Note 5: C_{OUT} is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.

AC Loading +7V OPEN ALL OTHER 500Ω *Includes jig and probe capacitance

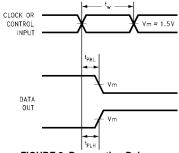


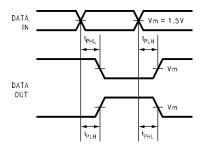
FIGURE 1. Standard AC Test Load

FIGURE 2. Propagation Delay, Pulse Width Waveforms

Amplitude	Rep. Rate	t _W	t _r	t _f
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

FIGURE 3. Test Input Signal Requirements

AC Waveforms



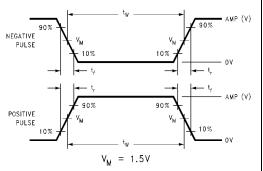
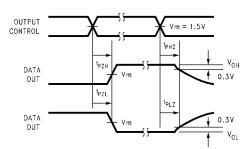


FIGURE 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

FIGURE 6. Test Input Signal Levels



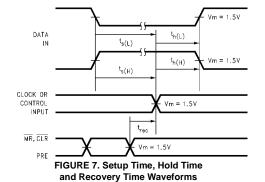
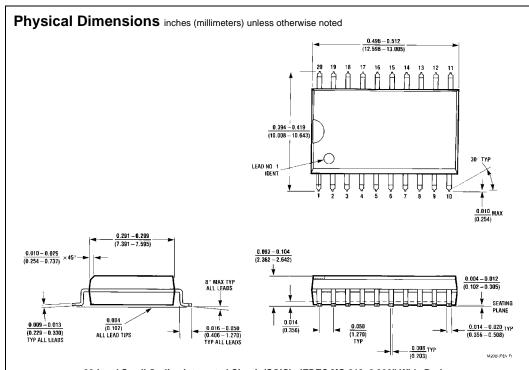
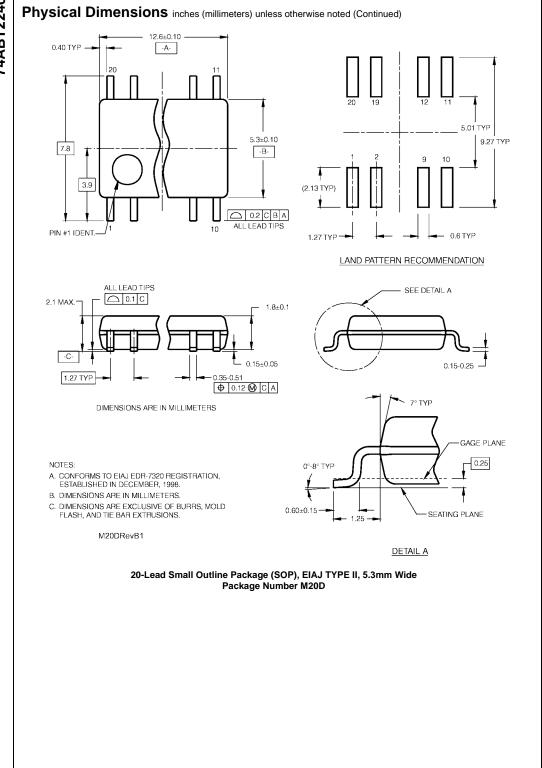
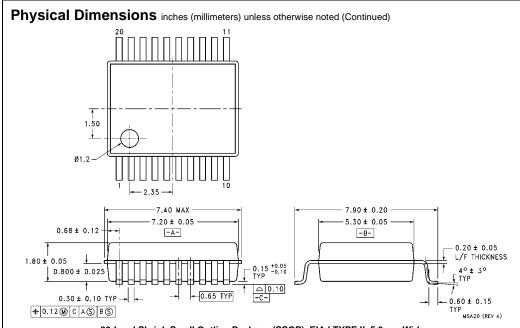


FIGURE 5. 3-STATE Output HIGH and LOW Enable and Disable Times

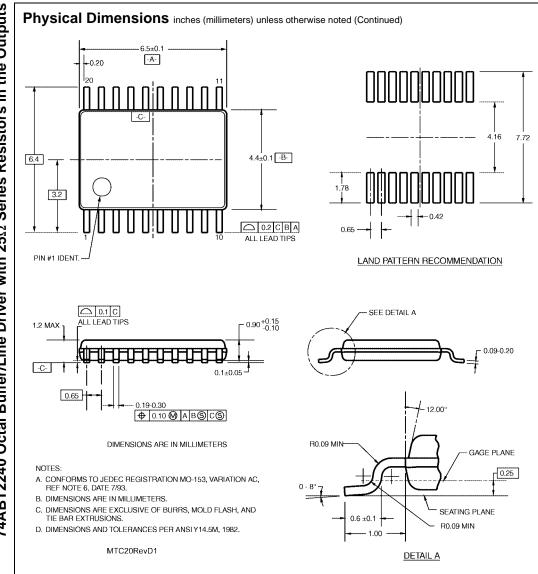


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20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20



20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20

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